

INTERNATIONAL ELECTROTECHNICAL COMMISSION

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SAFETY OF LASER PRODUCTS –

Part 1: Equipment classification and requirements

INTERPRETATION SHEET 1

This interpretation sheet has been prepared by IEC technical committee 76: Optical radiation safety and laser equipment.

The text of this interpretation sheet is based on the following documents:

FDIS	Report on voting
76/587/FDIS	76/593/RVD

Full information on the voting for the approval of this interpretation sheet can be found in the report on voting indicated in the above table.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

Subclause 4.3 Classification rules

This subclause is clarified by the following:

Introduction

For some complex extended sources or irregular temporal emissions, the application of the rules of subclause 4.3 may require clarification because of changes from IEC 60825-1:2007.

NOTE 1 For the purpose of this interpretation sheet, the abbreviation “AE” is used for “accessible emission”.

NOTE 2 The clarifications also apply in an equivalent way to MPE analysis, i.e. for Annex A.

1 Subclause 4.3 b) Radiation of multiple wavelengths

See IEC 60825-1:2014/ISH2.

2 Subclause 4.3 c) Radiation from extended sources

When using the default (simplified) evaluation method (subclause 5.4.2) for wavelengths ≥ 400 nm and $< 1\,400$ nm, the angle of acceptance may be limited to 100 mrad for determining the accessible emission to be compared against the accessible emission limit, except in the wavelength range 400 nm to 600 nm for durations longer than 100 s where the circular-cone angle of acceptance is not limited. When evaluating the emissions for comparison to the Class 3B AELs, the angle of acceptance is not limited.

3 Subclause 4.3 d) Non-uniform, non-circular or multiple apparent sources

In subclause 4.3 d), for comparison with the thermal retinal limits, the requirement to vary the angle of acceptance in each dimension might appear to contradict the labelling in Figure 1 and Figure 2 of subclause 5.4.3 where the field stop is labelled as circular.

Interpretation

A circular field stop is applicable for circularly symmetric images of the apparent source and for this case is consistent with the procedure given in subclause 4.3 d). For images of the apparent source that are not circularly symmetric, the simple example below clarifies the application of subclause 4.3 d).

A circular field stop with an angular subtense equal to $\alpha_{\max}$ is, however, applicable for non-circularly symmetric profiles if the analysis performed according to subclause 4.3 d), following variation of the angle of acceptance in each dimension, results in a solution which is equal to $\alpha_{\max}$ in both dimensions.

As a general principle, for whatever emission duration t the AEL is determined (such as the pulse duration, the pulse group duration or the time base for averaging of the power), the same emission duration t is also used to calculate $\alpha_{\max}(t)$.

The following example demonstrates the method described in subclause 4.3 d) to analyse irregular or complex images of a source. It is noted that the example is equivalent to the second part of the example ("Additional Remarks"; 6 mrad spacing instead of 3 mrad) B.9.1 of IEC TR 60825-14:2004 (however, for 6 mrad element spacing, the result in terms of which grouping is critical was not correct). The source is a diode array (Figure 1). The task is to determine the applicable AEL that limits the AE for Class 2. Each diode contributes a partial accessible emission AE of 1 mW that passes through a 7 mm aperture stop at the distance where the analysis is performed (i.e. a total power of 20 mW passes through the aperture stop), and the emission is continuous wave. The analysis requires determination of the most restrictive (maximum) ratio of AE over AEL by variation of the angle of acceptance in position and size to achieve different fields of view.